

TLP283,TLP283-4

PROGRAMMABLE CONTROLLERS

AC adapters for PDAs/ on-board power supplies

I/O interface boards

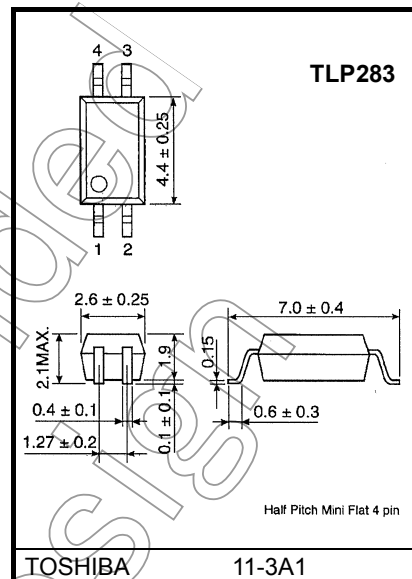
TLP283 and TLP283-4 is a very small and thin coupler,suitable for surface mount assembly in applications such as on-board power supplies,programmable controllers.

TLP283 and TLP283-4 consist of photo transistor,optically coupled to a gallium arsenide infrared emitting diode.

- Collector-Emitter Voltage : 100 V (MIN)
- Current Transfer Ratio : 100% (MIN)@IF=1mA
- 1 Pulse delay time(Note 1) : 100us(MAX)@IF=1mA,RL=10kΩ
- Isolation Voltage : 2500 Vrms (MIN)
- UL Recognized : UL1577 , File No. E67349

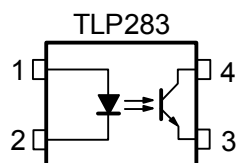
Note 1 : 1 Pulse delay time = tON+tOFF

Unit in mm

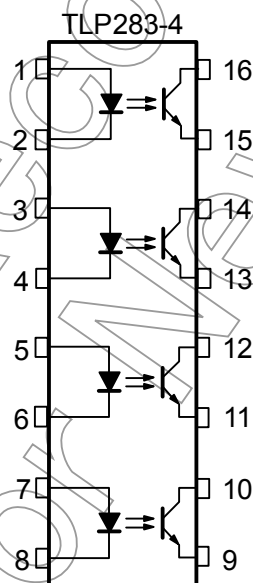


Weight: 0.05 g (typ.)

Pin Configuration (Top view)

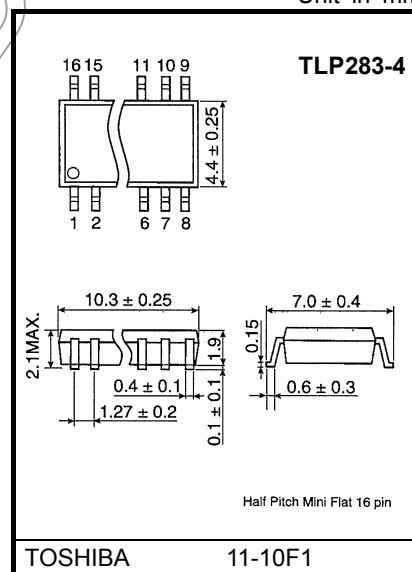


1:ANODE
2:CATHODE
3:EMITTER
4:COLLECTOR



1,3,5,7 :ANODE
2,4,6,8 :CATHODE
9,11,13,15 :EMITTER
10,12,14,16 :COLLECTOR

Unit in mm



Weight: 0.19 g (typ.)

Absolute Maximum Ratings (Ta = 25°C)

CHARACTERISTIC		SYMBOL	RATING		UNIT
			TLP283	TLP283-4	
LED	Forward Current	I _F	50		mA
	Forward Current Derating	ΔI _F /°C	-0.7 (Ta≥53°C)	-0.5 (Ta≥25°C)	mA /°C
	Pulse Forward Current	I _{FP}	1		A
	Reverse Voltage	V _R	5		V
	Junction Temperature	T _j	125		°C
DETECTOR	Collector-Emitter Voltage	V _{CEO}	100		V
	Emitter-Collector Voltage	V _{ECO}	7		V
	Collector Current	I _C	50		mA
	Collector Power Dissipation (1 Circuit)	P _C	150	100	mW
	Collector Power Dissipation Derating(Ta≥25°C) (1 Circuit)	ΔP _C /°C	-1.5	-1.0	mW /°C
	Junction Temperature	T _j	125		°C
Operating Temperature Range		T _{opr}	-55~100		°C
Storage Temperature Range		T _{stg}	-55~125		°C
Lead Soldering Temperature		T _{sol}	260 (10s)		°C
Total Package Power Dissipation (1 Circuit)		P _T	200	170	mW
Total Package Power Dissipation Derating (Ta≥25°C) (1 Circuit)		ΔP _T /°C	-2.0	-1.7	mW /°C
Isolation Voltage (Note2)		BV _S	2500(AC,1min,R.H.≤60%)		Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(Note2) Device considered a two terminal device : LED side pins shorted together and DETECTOR side pins shorted together.

Individual Electrical Characteristics (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
LED	Forward Voltage	V_F	$I_F = 10\text{ mA}$	1.0	1.15	1.3	V
	Reverse Current	I_R	$V_R = 5\text{ V}$	—	—	10	μA
	Capacitance	C_T	$V = 0, f = 1\text{ MHz}$	—	30	—	pF
DETECTOR	Collector-Emitter Breakdown Voltage	$V_{(BR)\text{ CEO}}$	$I_C = 0.5\text{ mA}$	100	—	—	V
	Emitter-Collector Breakdown Voltage	$V_{(BR)\text{ ECO}}$	$I_E = 0.1\text{ mA}$	7	—	—	V
	Collector Dark Current (Note3)	I_{CEO}	$V_{CE} = 48\text{ V}$, Ambient Light Below (100 lx)	—	0.01 (2)	0.1 (10)	μA
			$V_{CE} = 48\text{ V}$, $T_a = 85^\circ\text{C}$ Ambient Light Below (100 lx)	—	2 (4)	50 (50)	μA
	Capacitance (Collector to Emitter)	C_{CE}	$V = 0, f = 1\text{ MHz}$	—	10	—	pF

(Note3) Because of the construction, leak current might be increased by ambient light.
Please use photocoupler with less ambient light.

Coupled Electrical Characteristics (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Current Transfer Ratio	I_C / I_F	$I_F = 1 \text{ mA}$, $V_{CE} = 5 \text{ V}$	100	—	400	%
Saturated CTR	$I_C / I_F (\text{sat})$	$I_F = 1 \text{ mA}$, $V_{CE} = 0.4 \text{ V}$	50	—	—	%
Collector-Emitter Saturation Voltage	$V_{CE} (\text{sat})$	$I_C = 0.2 \text{ mA}$, $I_F = 1 \text{ mA}$	—	0.2	0.4	V
Off-State Collector Current	$I_C (\text{off})$	$V_F = 0.7 \text{ V}$, $V_{CE} = 48 \text{ V}$	—	—	10	μA

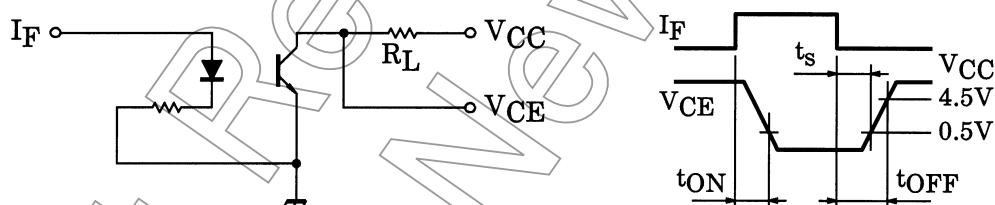
Isolation Characteristics (Ta = 25°C)

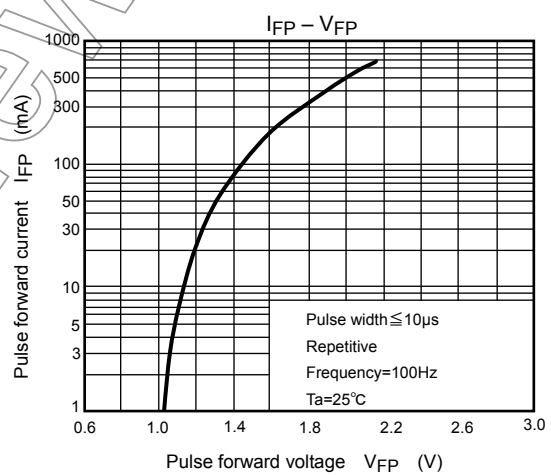
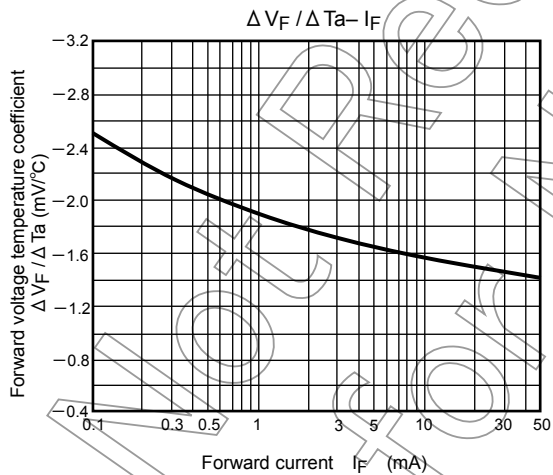
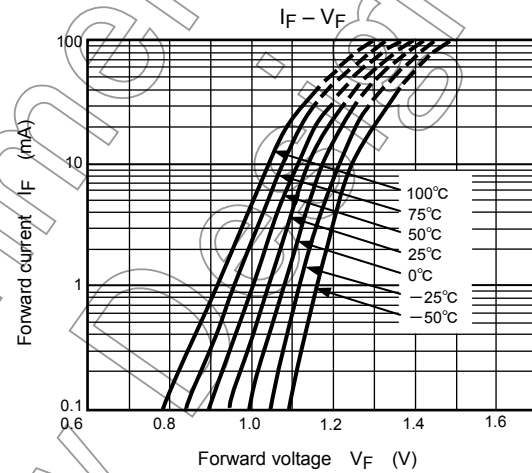
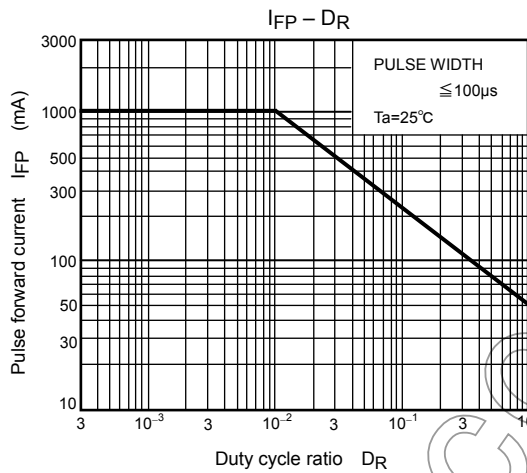
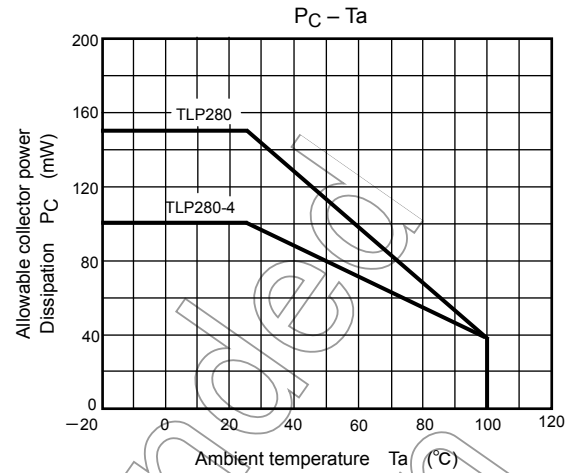
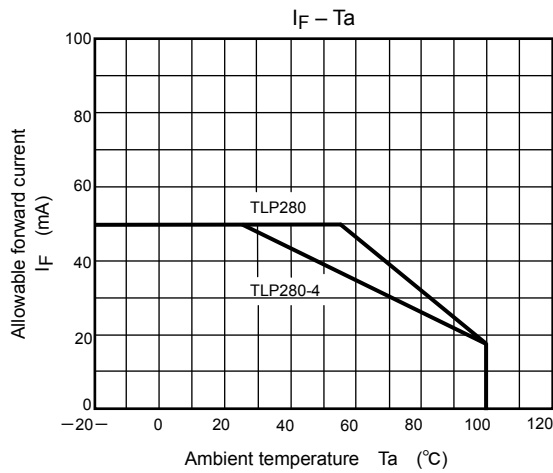
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Capacitance (Input to Output)	C_S	$V_S = 0 \text{ V}$, $f = 1 \text{ MHz}$	—	0.8	—	pF
Isolation Resistance	R_S	$V_S = 500 \text{ V}$, R.H. $\leq 60\%$	5×10^{10}	10^{14}	—	Ω
Isolation Voltage	BV_S	AC, 1 minute	2500	—	—	Vrms
		AC, 1 second, in OIL	—	5000	—	Vrms
		DC, 1 minute, in OIL	—	5000	—	Vdc

Switching Characteristics (Ta = 25°C)

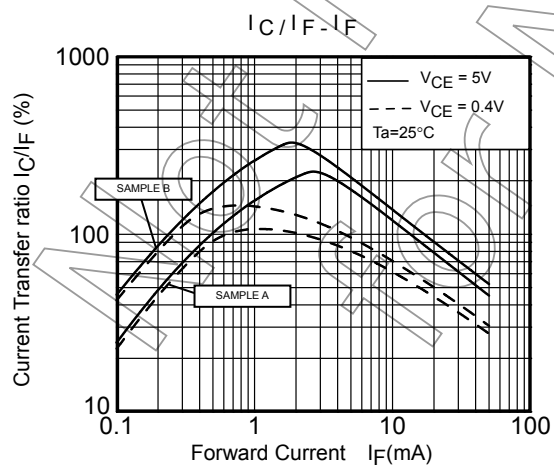
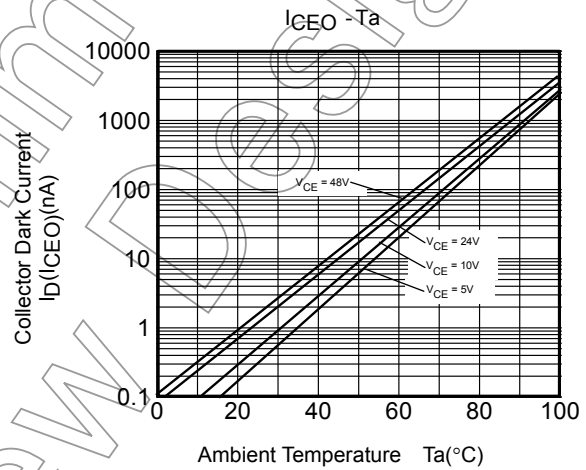
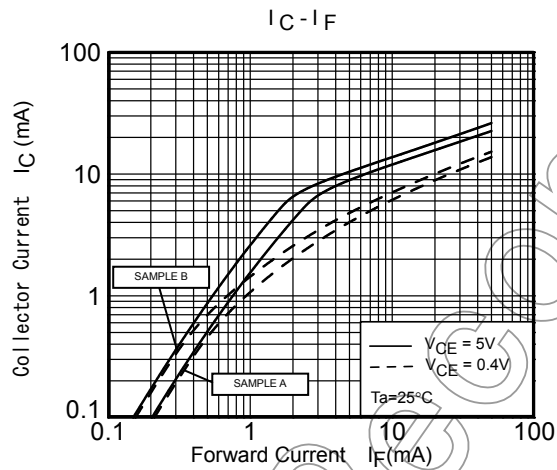
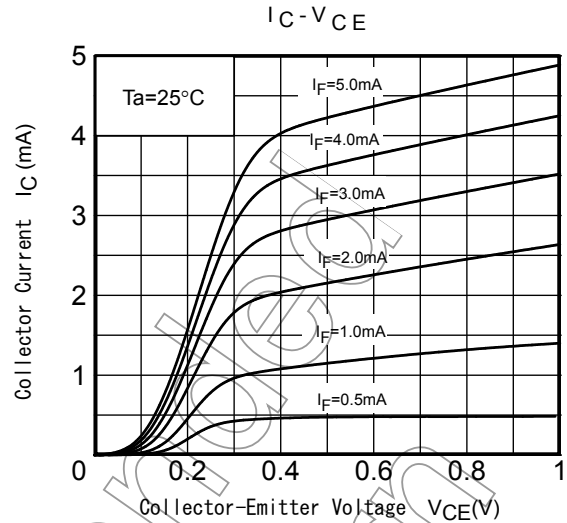
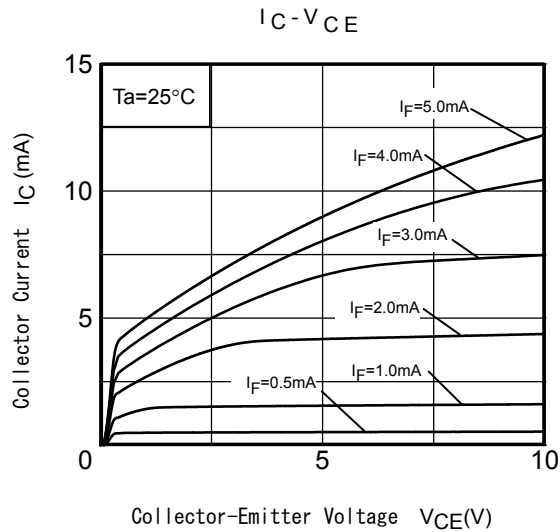
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Turn-On Time	t_{ON}	$V_{CC} = 5 \text{ V}$, $I_F = 1 \text{ mA}$ $R_L = 10 \text{ k}\Omega$	—	7.5	20	μs
Turn-Off Time	t_{OFF}		—	70	90	
1 Pulse delay time	$t_{ON} + t_{OFF}$		—	80	100	

(Fig.1) SWITCHING TIME TEST CIRCUIT

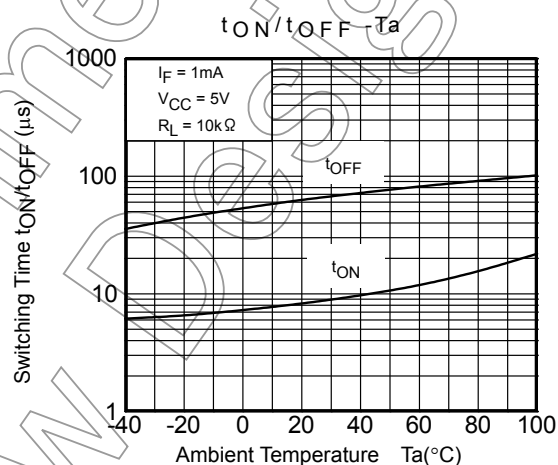
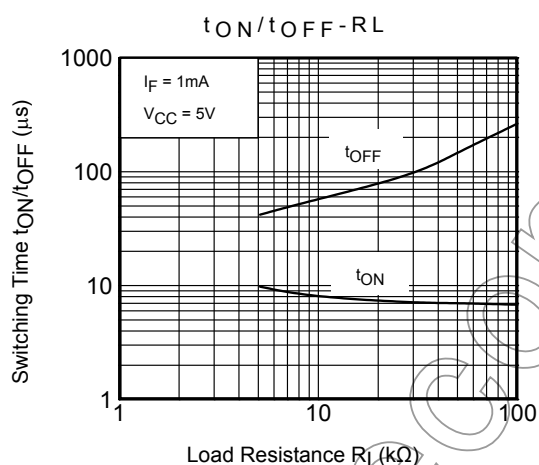
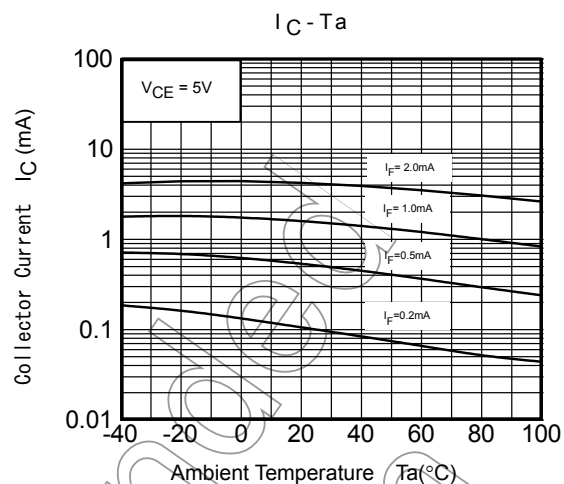
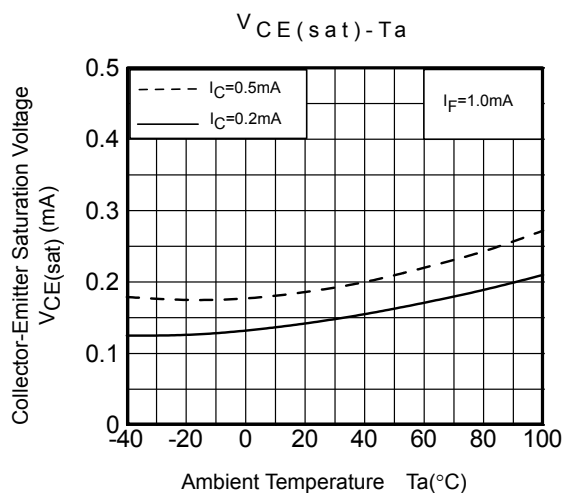




*: The above graphs show typical characteristics.



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